

APPLICATION DATA SHEET

APPLICATION INFORMATION

Application Type:: REGULAR
Subject Matter:: UTILITY
CD-ROM or CD-R?: NONE
Title:: SEMICONDUCTOR WAFER
INSPECTING METHOD
Attorney Docket Number:: 240626US2
Total Drawing Sheets:: 13

INVENTOR INFORMATION

Applicant Authority Type:: INVENTOR
Primary Citizenship Country:: Japan
Status:: FULL CAPACITY
Given Name:: Hideki
Family Name:: NARUOKA
City of Residence:: Tokyo
Country of Residence:: Japan
Street of Mailing Address:: c/o Renesas Technology Corp., 4-1,
Marunouchi 2-chome, Chiyoda-ku,
City of Mailing Address:: Tokyo
Country of Mailing Address:: Japan

CORRESPONDENCE INFORMATION

Correspondence Customer Number:: 22850

REPRESENTATIVE INFORMATION

Representative Customer Number:: 22850

FOREIGN PRIORITY INFORMATION

Application Number:	Country::	Filing Date::	Priority Claimed::
2002-293613	Japan	10/07/02	YES

ASSIGNMENT INFORMATION

Assignee Name:: Renesas Technology Corp.

Street of Mailing Address::

4-1, Marunouchi 2-chome,
Chiyoda-ku,

City of Mailing Address::

Tokyo

Country of Mailing Address::

Japan